Oral Sessions, Thursday afternoon, 9 August; *Signifies presenting author, when noted

Advanced Fundamental Parameters (Cotton Creek)

Chair: **J. Ullom,** National Institute of Standards & Technology, USA, joel.ullom@nist.gov

2:00 F-32 Invited - Advances in SI-Traceable Wavelength Metrology
C.I. Szabo*, Theiss Research and NIST, USA
L.T. Hudson, M.H. Mendenhall, A. Henins, J.P. Cline, NIST, USA

2:30 F-50 Invited - The use of Fundamental Parameters in XRF – An Industry Perspective
B. Vrebos*, P. Brouwer, Malvern Panalytical, The Netherlands

3:00 Break

3:30 F-39 New Measurements of X-ray Mass Attenuation Coefficients
Y. Ménesguen*, **M.-C. Lépy**, CEA, France
B. Beckhoff, PTB, Germany

3:50 F-45 Atomic Fundamental Parameter Determinations at PTB using Well-Known Synchrotron Radiation and Calibrated Instrumentation
B. Beckhoff*, P. Hönicke, I. Holfelder, Y. Kayser, M. Kolbe, J. Lubeck, M. Müller, B. Pollakowski-Herrmann, R. Unterumsberger, J. Weser, Physikalisch-Technische Bundesanstalt (PTB), Germany

4:10 F-52 Superconducting Microcalorimeters for X-ray Spectroscopy
J. Fowler, NIST Boulder Labs, USA

4:30 F-65 High-Precision Reference-Free Measurements of Soft X-ray Transitions with a Double Crystal Spectrometer
J. Machado*, Universidade Nova de Lisboa, Portugal and Sorbonne Université, France
J.P. Santos, P. Amaro, M. Guerra, Universidade Nova de Lisboa, Portugal
J.M. Isac, P. Indelicato, Sorbonne Université, France
C.I. Szabo, Theiss Research and NIST, USA
A. Gumberidze, GSI Helmholtzzentrum für Schwerionenforschung, Germany
G. Bian, Sorbonne Université, France and Sichuan University, China